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(Use several sheets if necessary)

APPLICANT

Khader S. Abdel-Hafez et al

FILING DATE

October 24, 2003

GROUP

2858

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>gpa</i>	4,503,537	03/1985	McAnney	371	25	
<i>gpa</i>	6,327,687	12/2001	Rajski	714	738	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>gpa</i>	B. Koenemann, "LFSR-Coded Test Patterns for Scan Designs", Proc., European Test Conf., pp. 237-242, 1991.
	/COPY UNAVAILABLE/

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation is considered, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.